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Application/Control No.	Applicant(s)/Patent under Reexamination
10/781,037	KIM ET AL.
Examiner	Art Unit

Leslie Pascal

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Subclass	Date	Examiner	
137	4/11/2007	LP	
	Subclass		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
see sea	rch notes	8/5/2007	LP	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
see search nptes	8/5/2007	LP	